

-200V P-Channel Enhancement Mode MOSFET

Description

The AP30P20NF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = -200V$ $I_D = -30A$

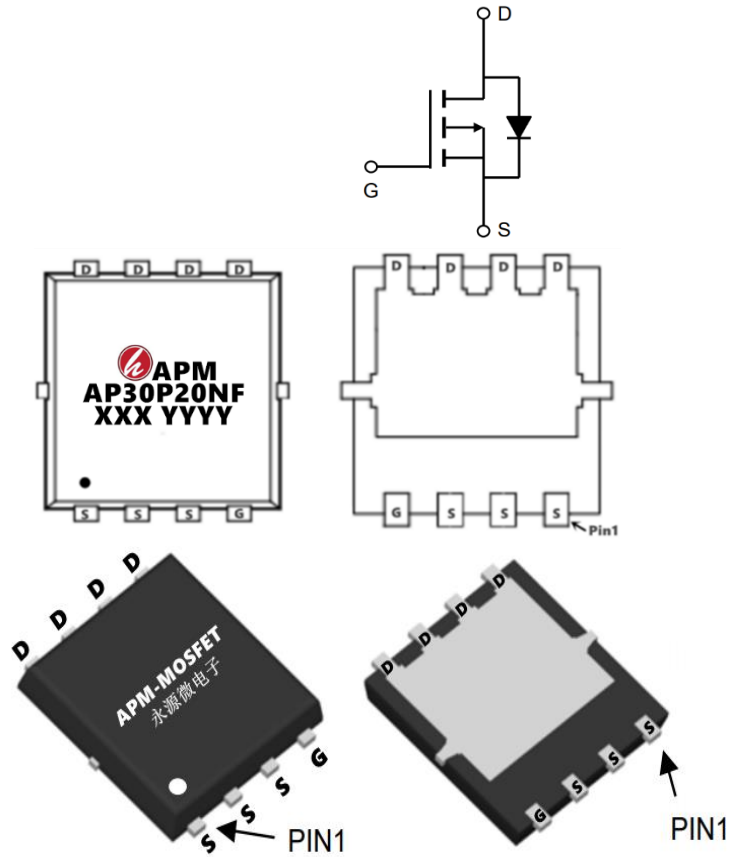
$R_{DS(ON)} < 380m\Omega$ @ $V_{GS}=10V$ (Type: 270m Ω)

Application

Brushless motor

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP30P20NF	PDFN5*6-8L	AP20P20NF XXX YYYY	5000

Absolute Maximum Ratings ($T_c=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-200	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_{D@T_A=25^{\circ}C}$	Continuous Drain Current, $-V_{GS}$ @ $-10V^1$	-30	A
$I_{D@T_A=70^{\circ}C}$	Continuous Drain Current, $-V_{GS}$ @ $-10V^1$	-15.8	A
I_{DM}	Pulsed Drain Current ²	-37	A
E_{AS}	Single Pulse Avalanche Energy ³	45	mJ
I_{AS}	Avalanche Current	7.7	A
$P_{D@T_A=25^{\circ}C}$	Total Power Dissipation ⁴	68	W
T_{STG}	Storage Temperature Range	-55 to 150	$^{\circ}C$
T_J	Operating Junction Temperature Range	-55 to 150	$^{\circ}C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	62	$^{\circ}C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	2.2	$^{\circ}C/W$

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Electrical Characteristics (T_J =25 °C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
VDS	Drain-source breakdown voltage	V _{GS} =0, I _D =-250 μA	-200	-220	-	V
VGS(th)	Gate-source threshold voltage	V _{DS} =V _{GS} , I _D =-250 μA	-2.5	-3.0	-3.5	
IGSS	Gate-source leakage	V _{DS} =0V, V _{GS} =± 20 V	-	-	± 100	nA
IDSS	Zero gate voltage drain current	V _{GS} =0V V _{DS} =-200V	-	-	-1	μA
RDS(on)	Drain-source on-state resistance ^a	V _{GS} =-10V I _D =-15A	-	270	380	mΩ
RDS(on)	Drain-source on-state resistance ^a	V _{GS} =-6.0V I _D =-10A	-	310	450	mΩ
gfs	Forward transconductance ^b	V _{DS} =-15 V, I _D =-3.8A	-	15	-	S
Ciss	Input capacitance	V _{GS} =0V V _{DS} =-25V, f=1MHz	-	2734	3700	pF
Coss	Output capaci tance		-	155	210	
Crss	Reverse transfer capacitance		-	103	140	
Qg	Total gate charge ^c	V _{GS} =-10V V _{DS} =-100V, I _D =-5.2A	-	55	85	nC
Qgs	Gate-source charge ^c		-	11	-	
Qgd	Gate-drain charge ^c		-	17	-	
Rg	Gate resistance	f= 1MHz	0.6	1.25	1.9	Ω
td(on)	Turn-on delay time ^c	V _{DD} =-100V, R _L =20.8Ω I _D ≅-4.8A, V _{GEN} =-10V, R _g =1Ω	-	16	25	ns
tr	Rise time ^c		-	5	10	
td(off)	Turn-off delay time ^c		-	35	55	
tf	Fall time ^c		-	5	10	
trr	Body diode reverse recovery time	I _F =-4 A, di/dt=100A/μs	-	101	205	ns
Qrr	Body diode reverse recovery charge		-	52	105	nC
ta	Reverse recovery fall time		-	87	-	ns
tb	Reverse recovery rise time		-	14	-	
ISM	Pulsed current		-	-	-37	A
VSD	Forward voltage	I _F = -5 A, V _{GS} = 0	-	-0.8	-1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、The EAS data shows Max. rating . The test condition is V_{DD} =-50V,V_{GS} =-10V,L=0.1mH,I_{AS} =-7.7A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

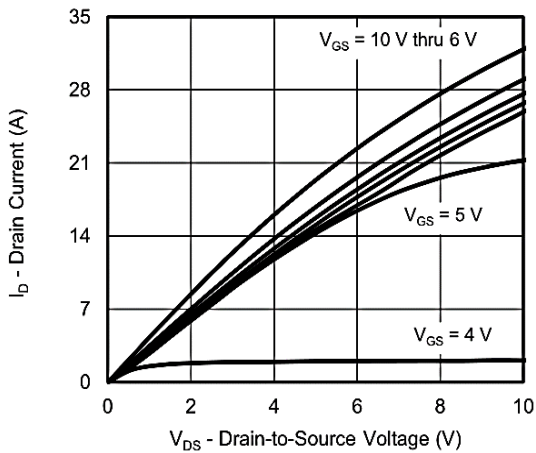


Fig1: Output Characteristics

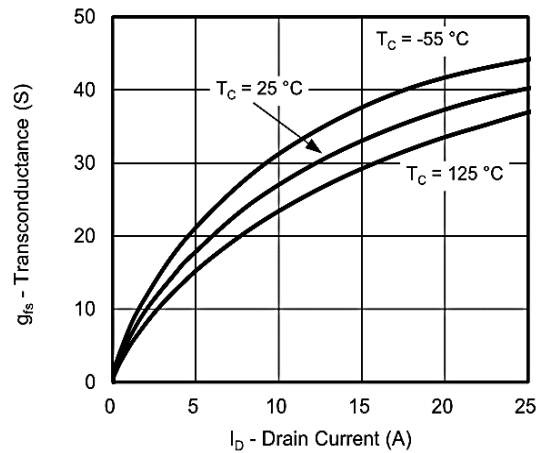


Fig2: Transfer Characteristics

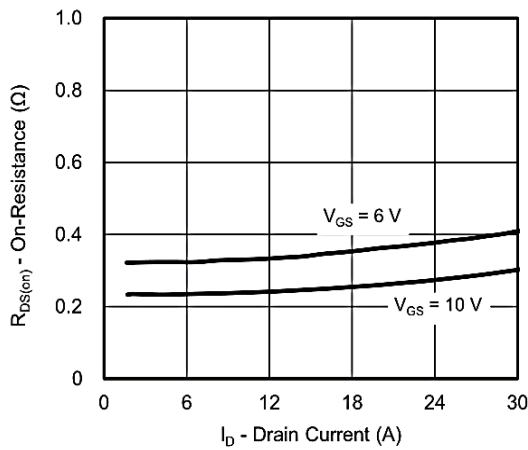


Fig3: On-Resistance vs. Drain Current

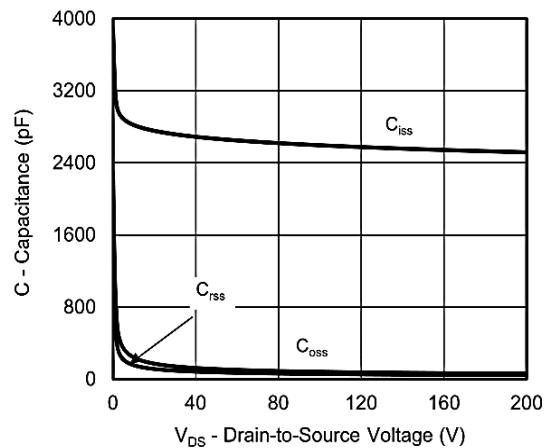


Fig4: Capacitance

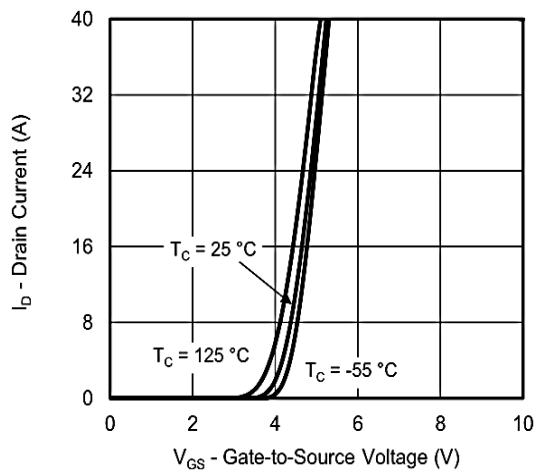


Fig5: Gate Charge

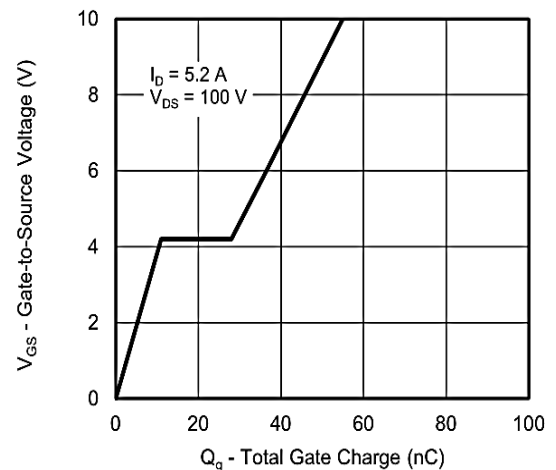


Fig6: On-Resistance vs. Junction Temperature



-200V P-Channel Enhancement Mode MOSFET

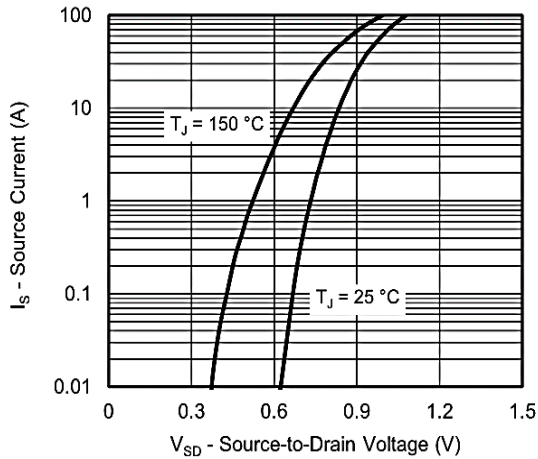


Fig7: Source-Drain Diode Forward Voltage

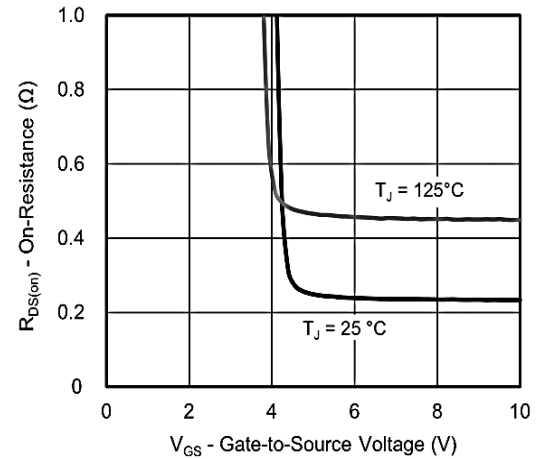


Fig8: On-Resistance vs. Gate-to-Source Voltage

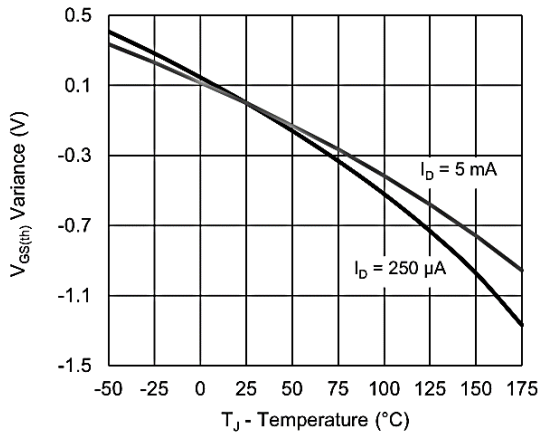


Fig9: Threshold Voltage

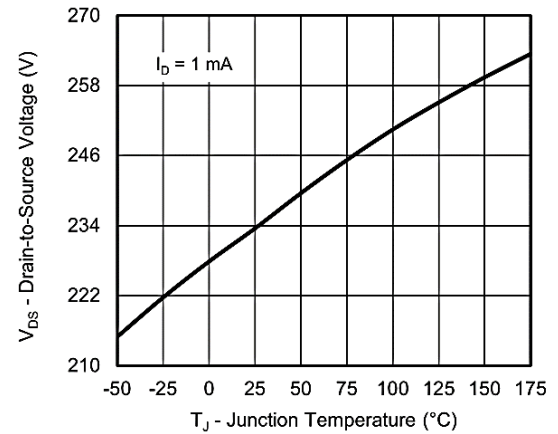


Fig10: Single Pulse Power, Junction-to-Ambient

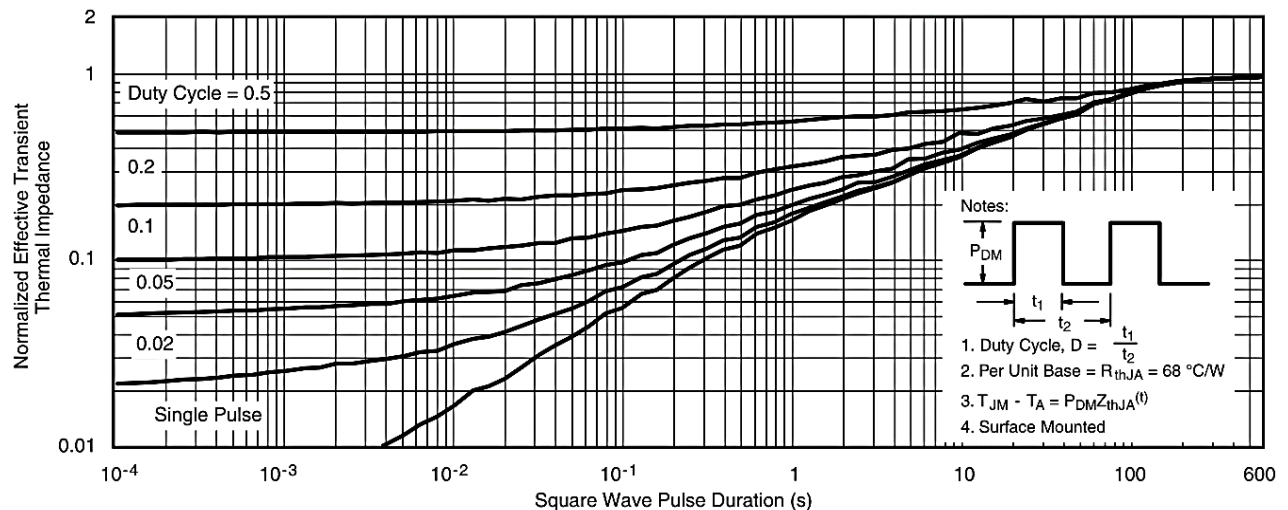
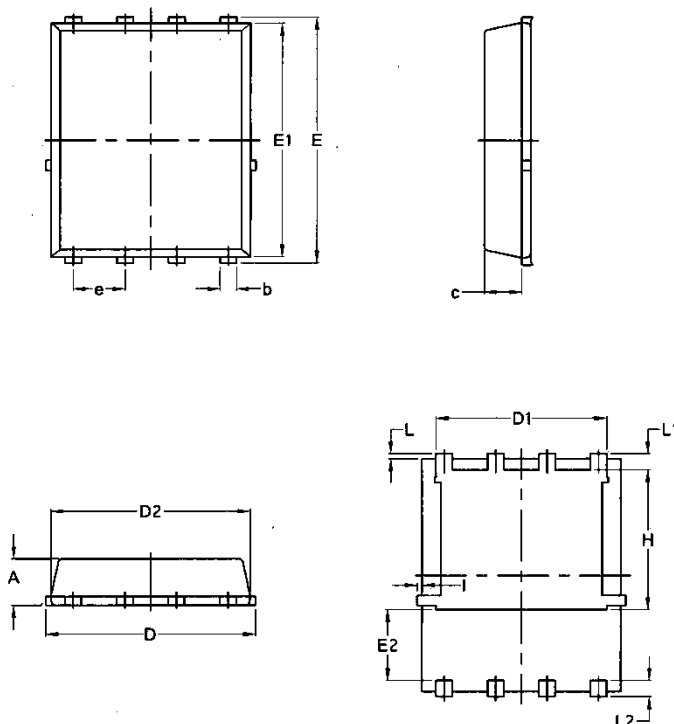


Fig11: Normalized Thermal Transient Impedance, Junction-to-Ambient

Package Mechanical Data-DFN5*6-8L-JQ Single



Symbol	Common			
	mm		Inch	
	Mim	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070

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Edition	Date	Change
REV1.0	2023/8/13	Initial release

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